

2048K X 8 BIT HIGH SPEED CMOS SRAM

REVISION HISTORY

Rev. 1.0

Revision Description Issue Date Jan.21.2014 Rev. 1.0 Initial Issue



2048K X 8 BIT HIGH SPEED CMOS SRAM

Rev. 1.0

FEATURES

■ Fast access time : 10ns

Low power consumption: Operating current:

90mA (TYP.) Standby current:

4mA (TYP.)

■ Single 3.3V power supply

■ All inputs and outputs TTL compatible

■ Fully static operation

■ Tri-state output

■ Data retension voltiage : 1.5V (MIN.)

■ Green package available

■ Package: 44-pin 400mil TSOP-II

48-ball 6mm x 8mm TFBGA

GENERAL DESCRIPTION

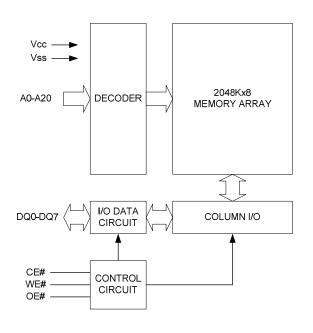
The LY61L20508A is a 16M-bit high speed CMOS static random access memory organized as 2048K words by 8 bits. It is fabricated using very high performance, high reliability CMOS technology. Its standby current is stable within the range of operating temperature.

The LY61L20508A operates from a single power supply of 3.3V and all inputs and outputs are fully TTL compatible

PRODUCT FAMILY

Product	Operating	Vcc Range Speed -		Power Dissipation		
Family	Temperature	vcc Range	Speed	Standby(I _{SB1} ,TYP.)	Operating(I _{CC} ,TYP.)	
LY61L20508A	0 ~ 70℃	2.7 ~ 3.6V	10ns	4mA	90mA	
LY61L20508A(I)	-40 ~ 85°C	2.7 ~ 3.6V	10ns	4mA	90mA	

FUNCTIONAL BLOCK DIAGRAM



PIN DESCRIPTION

SYMBOL	DESCRIPTION
A0 - A20	Address Inputs
DQ0 – DQ7	Data Inputs/Outputs
CE#	Chip Enable Input
WE#	Write Enable Input
OE#	Output Enable Input
Vcc	Power Supply
Vss	Ground

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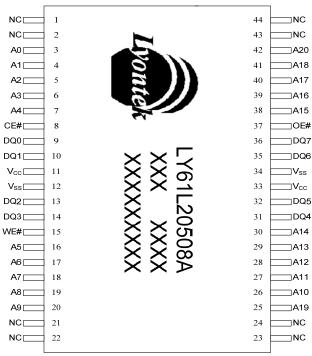
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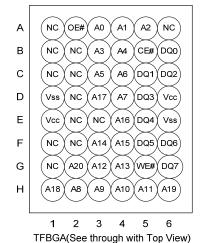
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PIN CONFIGURATION



TSOP-II



TFBGA(Top View)

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ABSOLUTE MAXIMUN RATINGS*

PARAMETER	SYMBOL	RATING	UNIT
Voltage on V _{CC} relative to V _{SS}	V_{T1}	-0.5 to 4.6	V
Voltage on any other pin relative to Vss	V_{T2}	-0.5 to Vcc+0.5	V
Operating Temperature	TA	0 to 70(C grade)	°C
Operating reinperature	IA	-40 to 85(I grade)	C
Storage Temperature	T _{STG}	-65 to 150	$^{\circ}$ C
Power Dissipation	P _D	1	W
DC Output Current	louт	50	mA

^{*}Stresses greater than those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to the absolute maximum rating conditions for extended period may affect device reliability.

TRUTH TABLE

MODE	CE#	OE#	WE#	I/O OPERATION	SUPPLY CURRENT
Standby	Н	X	Х	High-Z	I _{SB1}
Output Disable	L	Н	Н	High-Z	Icc
Read	L	L	Н	D _{оит}	Icc
Write	L	Х	L	Din	Icc

Note: $H = V_{IH}$, $L = V_{IL}$, X = Don't care.

DC ELECTRICAL CHARACTERISTICS

PARAMETER	SYMBOL	TEST CONDITION	MIN.	TYP. *4	MAX.	UNIT
Supply Voltage	Vcc		2.7	3.3	3.6	V
Input High Voltage	V _{IH} *1		2.2	-	Vcc+0.3	V
Input Low Voltage	V _{IL} *2		- 0.3	-	0.8	V
Input Leakage Current	ILI	$V_{CC} \ge V_{IN} \ge V_{SS}$	- 1	-	1	μA
Output Leakage Current	ILO	$V_{CC} \ge V_{OUT} \ge V_{SS},$ Output Disabled	- 1	-	1	μA
Output High Voltage	Vон	I _{OH} = -4mA	2.4	-	-	V
Output Low Voltage	Vol	I _{OL} = 8mA	-	-	0.4	V
Average Operating Power Supply Current	Icc	CE# \leq 0.2, Others at 0.2V or Vcc-0.2V I _{VO} = 0mA;f=max		90	120	mA
Standby Power Supply Current	I _{SB1}	CE# \geq V _{CC} - 0.2V, Others at 0.2V or V _{CC} - 0.2V	-	4	40	mA

Notes

^{1.} VIH(max) = VCC + 2.0V for pulse width less than 6ns.

^{2.} $V_{IL}(min) = V_{SS} - 2.0V$ for pulse width less than 6ns.

^{3.} Over/Undershoot specifications are characterized on engineering evaluation stage, not for mass production test.

^{4.} Typical values are included for reference only and are not guaranteed or tested. Typical valued are measured at V_{CC} = V_{CC}(TYP.) and T_A = 25°C



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CAPACITANCE (TA = 25°C, f = 1.0MHz)

PARAMETER	SYMBOL	MIN.	MAX	UNIT
Input Capacitance	Cin	-	8	pF
Input/Output Capacitance	Cı/o	-	10	pF

Note: These parameters are guaranteed by device characterization, but not production tested.

AC TEST CONDITIONS

Speed	10ns
Input Pulse Levels	0.2V to Vcc - 0.2V
Input Rise and Fall Times	3ns
Input and Output Timing Reference Levels	Vcc/2
Output Load	$C_L = 30pF + 1TTL$, $I_{OH}/I_{OL} = -4mA/8mA$

AC ELECTRICAL CHARACTERISTICS

(1) READ CYCLE

PARAMETER	SYM.	LY61L20	UNIT	
PARAMETER	STW.	MIN.	MAX.	UNII
Read Cycle Time	t _{RC}	10	-	ns
Address Access Time	taa	-	10	ns
Chip Enable Access Time	tace	-	10	ns
Output Enable Access Time	toe	-	4.5	ns
Chip Enable to Output in Low-Z	tclz*	2	-	ns
Output Enable to Output in Low-Z	tolz*	0	-	ns
Chip Disable to Output in High-Z	t _{CHZ} *	-	4	ns
Output Disable to Output in High-Z	tonz*	-	4	ns
Output Hold from Address Change	tон	2	-	ns

(2) WRITE CYCLE

PARAMETER	SYM.	LY61L20	LY61L20508A-10		
PARAIVIETER	STIVI.	MIN.	MAX.	UNIT	
Write Cycle Time	twc	10	-	ns	
Address Valid to End of Write	t _{AW}	8	-	ns	
Chip Enable to End of Write	tcw	8	-	ns	
Address Set-up Time	tas	0	-	ns	
Write Pulse Width	twp	8	-	ns	
Write Recovery Time	twr	0	-	ns	
Data to Write Time Overlap	t _{DW}	6	-	ns	
Data Hold from End of Write Time	t _{DH}	0	-	ns	
Output Active from End of Write	tow*	2	-	ns	
Write to Output in High-Z	twHz*	-	4	ns	

These parameters are guaranteed by device characterization, but not production tested.

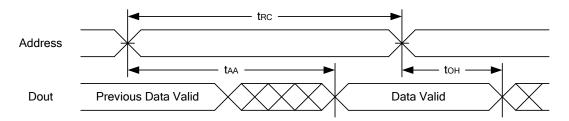


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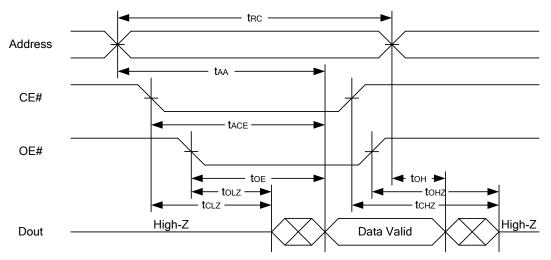
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TIMING WAVEFORMS

READ CYCLE 1 (Address Controlled) (1,2)



READ CYCLE 2 (CE# and OE# Controlled) (1,3,4,5)



Notes:

- 1.WE# is high for read cycle.
- 2.Device is continuously selected OE# = low, CE# = low.
- 3.Address must be valid prior to or coincident with CE# = low,; otherwise tAA is the limiting parameter.
- $4.t_{CLZ}$, t_{CLZ} , t_{CHZ} and t_{OHZ} are specified with C_L = 5pF. Transition is measured ± 500 mV from steady state.
- 5.At any given temperature and voltage condition, t_{CHZ} is less than t_{CLZ} , t_{OHZ} is less than t_{OLZ} .

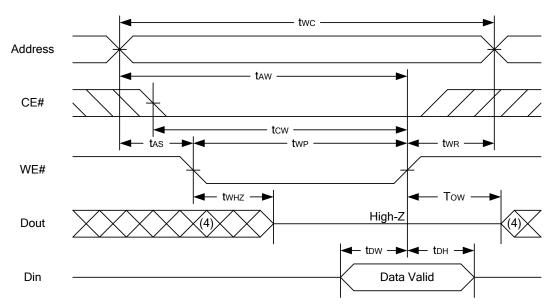
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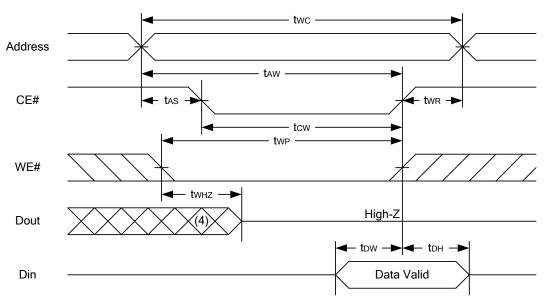
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WRITE CYCLE 1 (WE# Controlled) (1,2,3,5,6)



WRITE CYCLE 2 (CE# Controlled) (1,2,5,6)



Notes

- 1.WE#,CE#, LB#, UB# must be high during all address transitions.
- 2.A write occurs during the overlap of a low CE#, low WE#, LB# or UB# = low.
- 3.During a WE# controlled write cycle with OE# low, twp must be greater than twHZ + tpw to allow the drivers to turn off and data to be placed on the bus.
- 4. During this period, I/O pins are in the output state, and input signals must not be applied.
- 5.If the CE#, LB#, UB# low transition occurs simultaneously with or after WE# low transition, the outputs remain in a high impedance state.
- $6.t_{\text{OW}}$ and t_{WHZ} are specified with C_{L} = 5pF. Transition is measured $\pm 500 \text{mV}$ from steady state.

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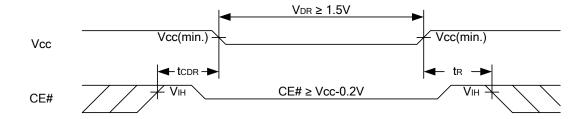
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DATA RETENTION CHARACTERISTICS

PARAMETER	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Vcc for Data Retention	V_{DR}	$CE\# \ge V_{CC} - 0.2V$	1.5	-	3.6	V
Data Retention Current		V_{CC} = 1.5V CE# \geq V _{CC} - 0.2V Others at 0.2V or V _{CC} - 0.2V	-	4	40	mA
Chip Disable to Data Retention Time	tcdr	See Data Retention Waveforms (below)	0	-	-	ns
Recovery Time	t _R		t _{RC*}	-	-	ns

t_{RC*} = Read Cycle Time

DATA RETENTION WAVEFORM



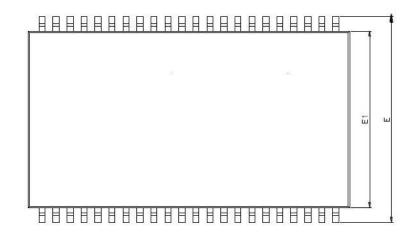


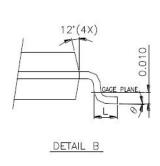
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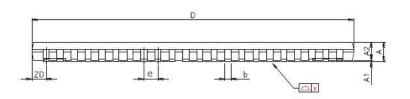
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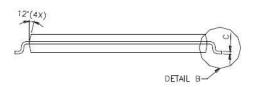
PACKAGE OUTLINE DIMENSION

44-pin 400mil TSOP-II Package Outline Dimension









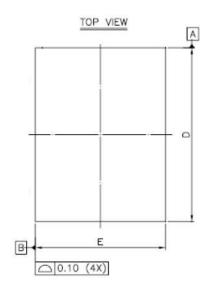
SYMBOLS	DIMENSI	ONS IN MILL	METERS.	DIM	DIMENSIONS IN MILS			
STWIBULS	MIN.	NOM.	MAX.	MIN.	NOM.	MAX.		
Α	-	-	1.20	-	-	47.2		
A1	0.05	0.10	0.15	2.0	3.9	5.9		
A2	0.95	1.00	1.05	37.4	39.4	41.3		
b	0.30	-	0.45	11.8	-	17.7		
С	0.12	-	0.21	4.7	-	8.3		
D	18.212	18.415	18.618	717	725	733		
E	11.506	11.760	12.014	453	463	473		
E1	9.957	10.160	10.363	392	400	408		
е	-	0.800	-	-	31.5	-		
L	0.40	0.50	0.60	15.7	19.7	23.6		
ZD	-	0.805	-	-	31.7	-		
У	-	-	0.076	-	-	3		
θ	0°	3°	6°	0°	3°	6°		

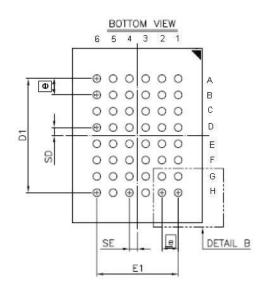


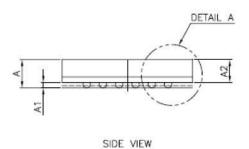
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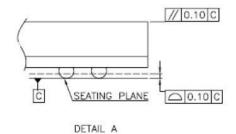
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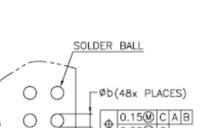
48-ball 6mm × 8mm TFBGA Package Outline Dimension











0.08M C

CVAL	D	IMENSIO (mm)	N	DIMENSION (inch)			
SYM.	MIN.	NOM.	MAX.	MIN.	NOM.	MAX.	
Α	_	_	1.40	_	_	0.055	
A1	0.20	0.25	0.30	0.008	0.010	0.012	
A2	_	_	1.05	_	_	0.041	
b	0.30	0.35	0.40	0.012	0.014	0.016	
D	7.95	8.00	8.05	0.313	0.315	0.317	
D1	5	.25 BS0)	0.207 BSC			
Ε	5.95	6.00	6.05	0.234	0.236	0.238	
E1	3	3.75 BSC			.148 BS	SC SC	
SE	0.375 TYP			0	.015 TY	'P	
SD	0.375 TYP			0	.015 TY	P	
e	0	.75 BS0		0	.030 BS	SC	

NOTE:

CONTROLLING DIMENSION: MILLIMETER.
REFERENCE DOCUMENT: JEDEC MO-207.

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DETAIL B



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ORDERING INFORMATION

Package Type	Access Time (Speed/ns)	Temperature Range(℃)	Packing Type	Lyontek Item No.
44-Pin 400mil TSOP-II	10	0℃~70℃	Tray	LY61L20508AML-10
			Tape Reel	LY61L20508AML-10T
		-40℃~85℃	Tray	LY61L20508AML-10I
			Tape Reel	LY61L20508AML-10IT
48-Ball 6mm x 8mm TFBGA	10	0℃~70℃	Tray	LY61L20508AGL-10
			Tape Reel	LY61L20508AGL-10T
		-40℃~85℃	Tray	LY61L20508AGL-10I
			Tape Reel	LY61L20508AGL-10IT



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